N-channel TrenchMOS logic level FET

5 October 2012

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel MOSFET in a SOT404 package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True logic level gate with Vgst(th) rating of greater than 0.5V at 175 °C

1.3 Applications

- 12V, 24V and 48V Automotive systems
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

1.4 Quick reference data

Table 1. Qui	ck reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	80	V
I _D	drain current	V _{GS} = 5 V; T _{mb} = 25 °C; <u>Fig. 1</u>	[1]	-	-	75	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 2</u>		-	-	182	W
Static charact	eristics	·	1				
R _{DSon}	drain-source on-state resistance	V _{GS} = 5 V; I _D = 20 A; T _j = 25 °C; <u>Fig. 11</u>		-	8.3	11	mΩ
Dynamic char	acteristics				1		
Q _{GD}	gate-drain charge	V _{GS} = 5 V; I _D = 20 A; V _{DS} = 64 V; Fig. 13; Fig. 14		-	16	-	nC

[1] Continuous current is limited by package.





N-channel TrenchMOS logic level FET

2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	D
2	D	drain		
3	S	source		G-UF44
mb	D	mounting base; connected to drain	D2PAK (SOT404)	mbb076 S

3. Ordering information

Table 3. Ordering information							
Type number	Package						
	Name	Description	Version				
BUK9611-80E	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404				

4. Marking

Table 4. Marking codes	
Type number	Marking code
BUK9611-80E	BUK9611-80E

5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

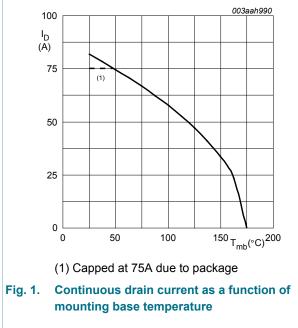
Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	80	V
V _{DGR}	drain-gate voltage	R _{GS} = 20 kΩ		-	80	V
V_{GS}	gate-source voltage	$T_j \le 175 \ ^{\circ}C; Pulsed$	[1][2]	-15	15	V
		T _j ≤ 175 °C; DC		-10	10	V
I _D	drain current	T _{mb} = 25 °C; V _{GS} = 5 V; <u>Fig. 1</u>	[3]	-	75	А
		T _{mb} = 100 °C; V _{GS} = 5 V; <u>Fig. 1</u>		-	58	А
I _{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \ \mu$ s; Fig. 4		-	327	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 2</u>		-	182	W
T _{stg}	storage temperature			-55	175	°C
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BUK9611-80E

N-channel TrenchMOS logic level FET

Symbol	Parameter	Conditions		Min	Мах	Unit
Tj	junction temperature			-55	175	°C
Source-drain	diode					
l _S	source current	T _{mb} = 25 °C	[3]	-	75	А
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^\circ C$		-	327	А
Avalanche ru	ıggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$\label{eq:ID} \begin{split} I_D &= 75 \text{ A}; \text{V}_{\text{sup}} \leq 80 \text{V}; \text{R}_{\text{GS}} = 50 \Omega; \\ \text{V}_{\text{GS}} &= 5 \text{V}; \text{T}_{j(\text{init})} = 25 ^{\circ}\text{C}; \text{ unclamped}; \\ \hline \text{Fig. } 3 \end{split}$	[4][5]	-	145	mJ

- Accumulated pulse duration up to 50 hours delivers zero defect ppm [1]
- [2] Significantly longer life times are achieved by lowering T_{j} and or V_{GS}
- [3] Continuous current is limited by package.
- Single-pulse avalanche rating limited by maximum junction temperature of 175 °C. Refer to application note AN10273 for further information. [4]
- [5]



 $V_{GS} \ge 5V$

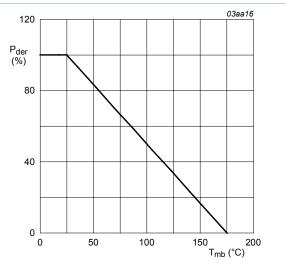
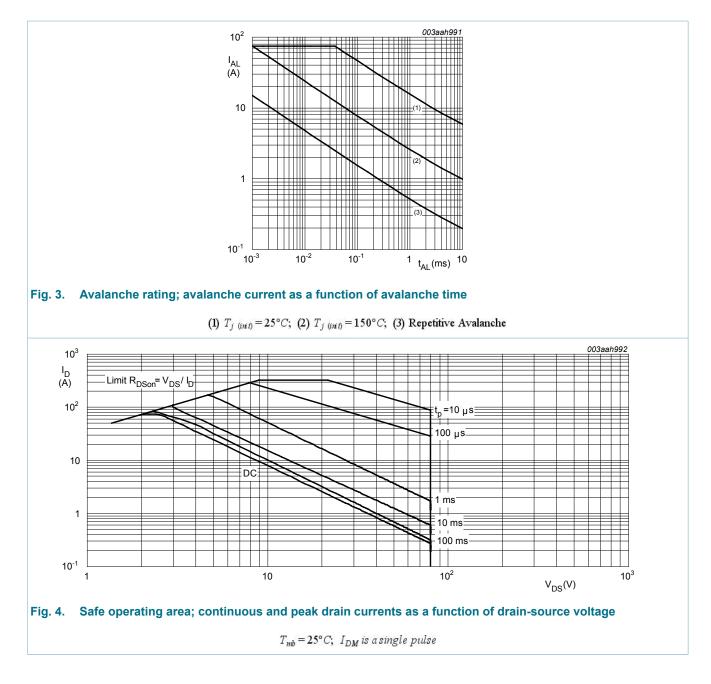


Fig. 2. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

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N-channel TrenchMOS logic level FET

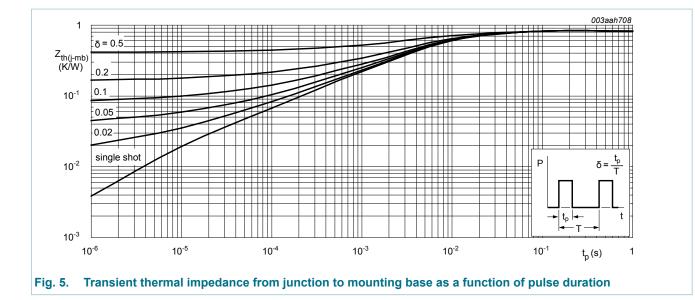


6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	<u>Fig. 5</u>	-	-	0.82	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	minimum footprint ; mounted on a printed-circuit board	-	50	-	K/W

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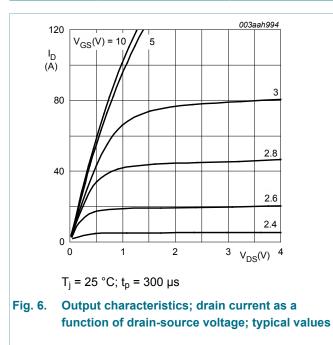


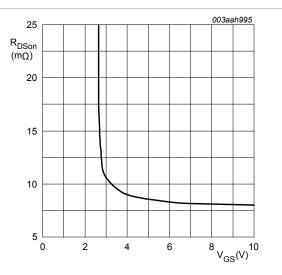
Characteristics 7.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics					
V _{(BR)DSS}	drain-source	I_D = 250 µA; V_{GS} = 0 V; T_j = 25 °C	80	-	-	V
	breakdown voltage	I_D = 250 µA; V_{GS} = 0 V; T_j = -55 °C	72	-	-	V
V _{GS(th)}	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; Fig. 9; Fig. 10	1.4	1.7	2.1	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ Fig. 9	-	-	- - 2.1 2.45 - 2.45 - 30 100 100 100 11 10 10 27.3	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ Fig. 9	0.5	-	-	V
I _{DSS}	drain leakage current	V_{DS} = 80 V; V_{GS} = 0 V; T_j = 25 °C	-	0.03	1	μA
		V _{DS} = 80 V; V _{GS} = 0 V; T _j = 175 °C	-	-	500	μA
I _{GSS}	gate leakage current	V_{GS} = 10 V; V_{DS} = 0 V; T_j = 25 °C	-	2	100	nA
		V_{GS} = -10 V; V_{DS} = 0 V; T_j = 25 °C	-	2	100	nA
R _{DSon}	drain-source on-state	V _{GS} = 5 V; I _D = 20 A; T _j = 25 °C; <u>Fig. 11</u>	-	8.3	11	mΩ
	resistance	V _{GS} = 10 V; I _D = 20 A; T _j = 25 °C; Fig. 11	-	7.8	- - 1.7 2.1 1.7 2.45 - 2.45 - - 0.03 1 - 500 2 100 2.3 11 7.8 10 - 27.3 48.8 -	mΩ
		V _{GS} = 5 V; I _D = 20 A; T _j = 175 °C; Fig. 12; Fig. 11	-	-	27.3	mΩ
Dynamic ch	aracteristics	· · ·				
Q _{G(tot)}	total gate charge	I_D = 20 A; V_{DS} = 64 V; V_{GS} = 5 V;	-	48.8	-	nC
Q _{GS}	gate-source charge	Fig. 13; Fig. 14	-	12.2	-	nC

N-channel TrenchMOS logic level FET

Symbol	Parameter	Conditions	Mi	in	Тур	Мах	Unit
Q _{GD}	gate-drain charge		-		16	-	nC
C _{iss}	input capacitance	V _{GS} = 0 V; V _{DS} = 25 V; f = 1 MHz;	-		5362	7149	pF
C _{oss}	output capacitance	$T_{j} = 25 \text{ °C}; \text{ Fig. 15}$ $V_{DS} = 60 \text{ V}; \text{ R}_{L} = 3 \Omega; \text{ V}_{GS} = 5 \text{ V}; \text{ R}_{G(ext)} = 5 \Omega$ from upper edge of drain mounting base to center of die from source lead to source bonding pad $I_{S} = 20 \text{ A}; \text{ V}_{GS} = 0 \text{ V}; \text{ T}_{j} = 25 \text{ °C}; \text{ Fig. 16}$ $I_{S} = 20 \text{ A}; \text{ d}_{S}/\text{d}t = -100 \text{ A}/\mu\text{s}; \text{ V}_{GS} = 0 \text{ V};$	-		350	420	pF
C _{rss}	reverse transfer capacitance		-		185	253	pF
t _{d(on)}	turn-on delay time	V_{DS} = 60 V; R_L = 3 Ω ; V_{GS} = 5 V;	-		29.6	-	ns
t _r	rise time	$R_{G(ext)} = 5 \Omega$	-		63.9	-	ns
t _{d(off)}	turn-off delay time		-		58.4	-	ns
t _f	fall time		-		53.2	-	ns
L _D	internal drain inductance		-		2.5	-	nH
L _S	internal source inductance		-		7.5	-	nH
Source-dra	in diode						
V _{SD}	source-drain voltage	I_{S} = 20 A; V_{GS} = 0 V; T_{j} = 25 °C; <u>Fig. 16</u>	-		0.82	1.2	V
t _{rr}	reverse recovery time	I_{S} = 20 A; dI _S /dt = -100 A/µs; V _{GS} = 0 V;	-		37.7	-	ns
Qr	recovered charge	V _{DS} = 25 V	-		61.5	-	nC



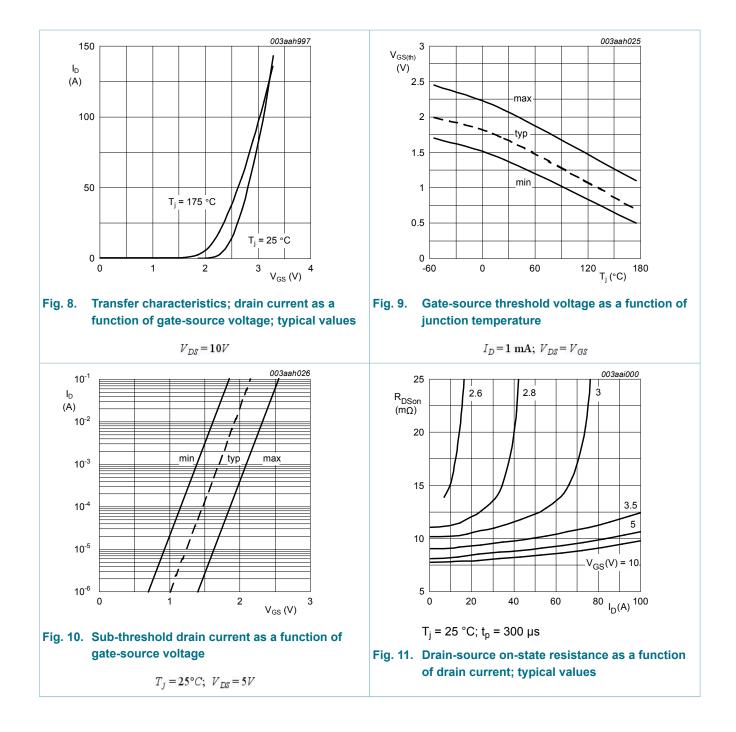




 $T_j = 25^{\circ}C; \ I_D = 20A$

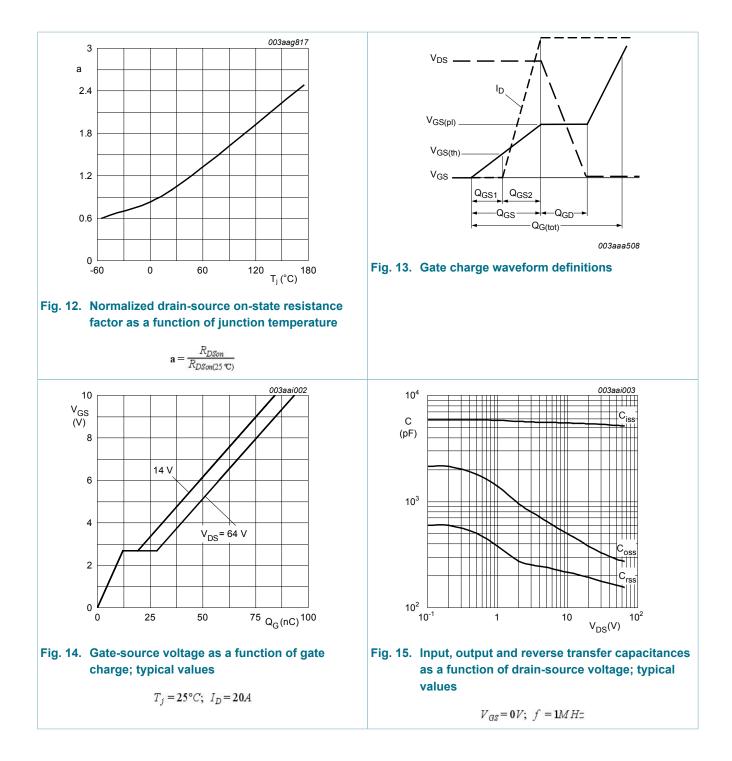
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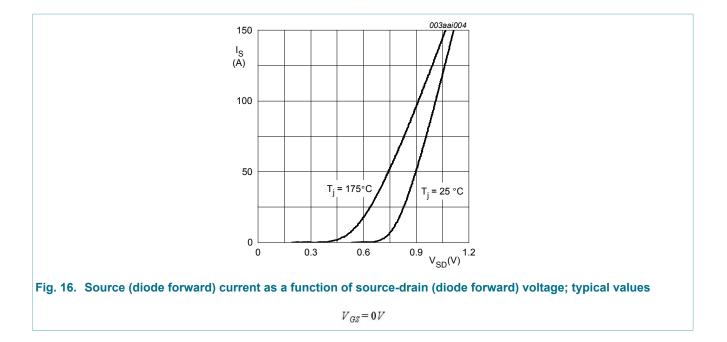
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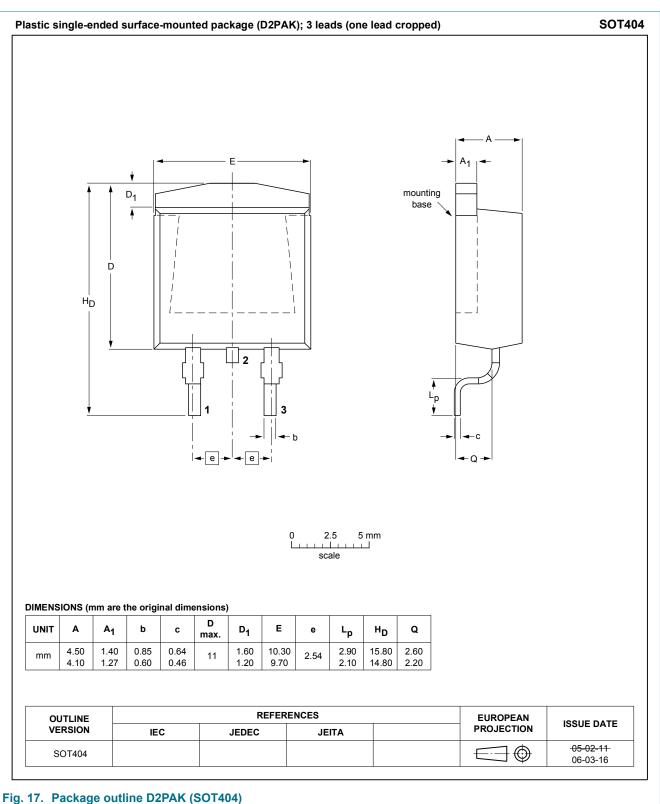
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Package outline 8.



BUK9611-80E

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N-channel TrenchMOS logic level FET

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Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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N-channel TrenchMOS logic level FET

10. Contents

1	Product profile	. 1
1.1	General description	. 1
1.2	Features and benefits	1
1.3	Applications	. 1
1.4	Quick reference data	. 1
2	Pinning information	.2
3	Ordering information	.2
4	Marking	. 2
5	Limiting values	2
6	Thermal characteristics	4
7	Characteristics	.5
8	Package outline	10
9	Legal information	11
9.1	Data sheet status	11
9.2	Definitions	11
9.3	Disclaimers	11
9.4	Trademarks	12

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